

KH7700

Quartz Crystals Temperature Test System

with
PI - network Measurement



New State of the Art Features

- Multi-Tasking operation in Microsoft Windows® allows testing in background while generating reports and graphs by operator
- Test limits such as Temperature range and ppm can be changed after actual testing, this gives better reports and graphs presentation for customers
- Support both “Direct impedance measure” & “Phy. CL “ for FL measurement (Optional Phy CL head)
- User Programmable Drive Level : 10nW - 1mW (max and min power depends on Rr of crystal)
- Crystal Measurement through passive π network techniques with KH1800 / KH1820 network analyzer
- Multiple crystal types may be accommodated in the same temperature run
- Automatic C0 cancellation for high frequencies
- User friendly system operation including menu driven, mouse operation and easy system calibration
- Perform pass/fail testing to user specified limits
- Stacked dual row test wheels can hold up to 508 crystals per chamber (depends on crystal type)
- Measures : Fs, FL, Rs, CL, C0, C1, L1, Q, Ts, C0/C1, DF, DLD, Spurious scan, Fs/T, and FL/T
- Optional Chinese operating software
- Frequency Range : KH1800 : 1 - 120 MHz
KH1820 : 1 - 240 MHz

Standard System Configuration

- KH1800 or KH1820 Crystal π Network Analyzer
- KH7700 System Operating Software & System Cabling
- KM5901 Switch Box
- Work table



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- KH7220 Chamber
- Dual Row π network test head and 4 inch cover
- Dual row test wheel (for 49U, 49S Leaded-type crystals)
- Industrial computer or Lenovo Computer (or compatible) with Windows® XP (From better performance, suggest to use Intel Core 2 Duo E4500 2.2 GHz or above with 1G RAM, USB port, PCI slot (For long card) with 3.3V & 5V.

System Options

- Dual Chamber, Multi-Task, Time sharing Testing
- Stacked Dual Row π Network Test Head and 8" cover
- Test Head & Disk Pallet (for SMD crystals 7050, 5032, 3225, 2520.....etc)
- Chinese Language Support

Software Capabilities

Easy Test Set up and Operation

- The user friendly Windows® environment eliminates the need of remembering how to operate or program a test.

Other Standard Reports

- Printout of Crystal Failures
- Printout of Crystal Measurements
- Printout of Frequency and Resistance vs. Temperature
- Plot of Frequency and Resistance vs. Temperature
- Tabular Printout of the Curve-fit Data

- Data Transfer to other standard applications, such as dBase, Lotus

Temperature Characteristic Graph

Graph showing Frequency (f) and Resistance (R) vs. Temperature (T) for crystal A1. The x-axis represents Temperature in °C, ranging from -30.0 to 145.0. The left y-axis represents Frequency (f) in MHz, ranging from 10.43 to 25.00. The right y-axis represents Resistance (R) in ohms, ranging from 0.00 to 145.00. The graph shows a red curve for frequency and a blue curve for resistance.

Crystal Data Table

Crystal	Temp. °C	Fs ppm	Rs ohm	CO pF	CI pF	Q	L mH	C0/C1
A1	25.0	29.6	49.5	3.3	7.2	139.3	344.2	453.4
A2	25.0	-14.5	27.7	3.4	7.5	237.4	328.4	447.3
A3	25.0	23.7	37.9	3.4	7.5	276.3	333.1	457.6
A4	25.0	30.0	39.7	3.4	6.7	187.0	371.1	503.8
A5	25.0	15.0	44.3	3.4	7.0	161.5	357.1	485.5
A6	25.0	21.9	87.1	3.4	7.1	80.8	351.5	477.0

Typical Report Format

Specification herein are preliminary, and are subject to change without prior notice.

Photo shown is for reference only.

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